ISSUE CLASSIFICATION
Class | Subclass

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
SCANNED	Q.A.	

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/695726	D	378 250	310	2876 2881	Fernandez

APPLICANTS

Shing Lee

TITLE

Film thickness measurement using electron-beam induced x-ray microanalysis

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL			CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
INTERNATIONAL CLASSIFICATION								
						☐ Continued on Issue Slip Inside File Jacket		

☐ TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
☐ The term of this patent subsequent to _____ (date) has been disclaimed.	(Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
☐ The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____	(Primary Examiner) (Date)			ISSUE FEE	
				Amount Due	Date Paid
☐ The terminal ____ months of this patent have been disclaimed.	(Legal Instruments Examiner) (Date)			ISSUE BATCH NUMBER	

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